

Title:	Performance report for SiT3372, 148.351648 MHz, LVDS		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 12, 2018

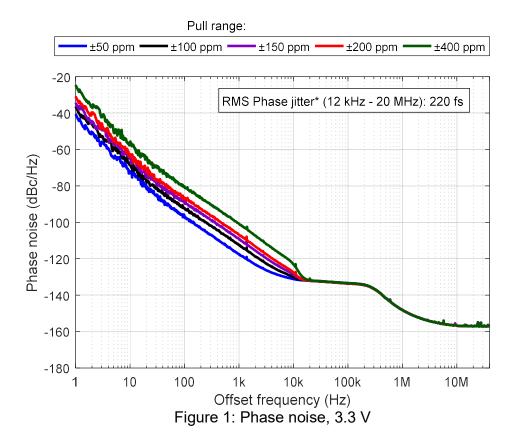
Performance report for SiT3372 - 148.351648 MHz, LVDS

This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



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*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz						
Frequency offset	Pull range (ppm)					
(Hz)	±50	±100	±150	±200	±400	
1	-40.6	-36.4	-34.4	-30.8	-24.6	
10	-73.1	-67.2	-64.0	-64.0	-55.8	
100	-96.6	-92.1	-88.8	-86.7	-80.2	
1 K	-117.6	-112.5	-109.1	-106.9	-100.8	
10 K	-131.1	-130.0	-128.8	-127.5	-123.1	
100 K	-133.6	-133.6	-133.4	-133.6	-133.4	
1 M	-148.1	-148.2	-148.1	-148.1	-148.1	
10 M	-156.8	-156.8	-156.8	-156.8	-156.8	
40 M	-157.1	-157.2	-157.1	-157.1	-157.2	

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Table 2: Integrated Phase jitter

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Darameter	Units	Pull range (ppm)	
Parameter	Utilits	±50 to ±400	
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	100	
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	220	



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Figure 2: Output waveform, 2.5 V



Figure 3: Output waveform, 3.3 V

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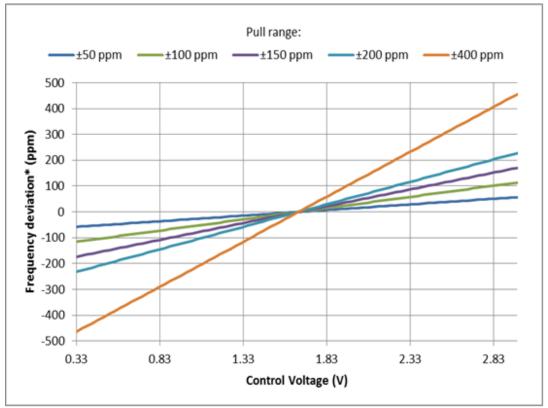


Figure 4: Frequency pull characteristic



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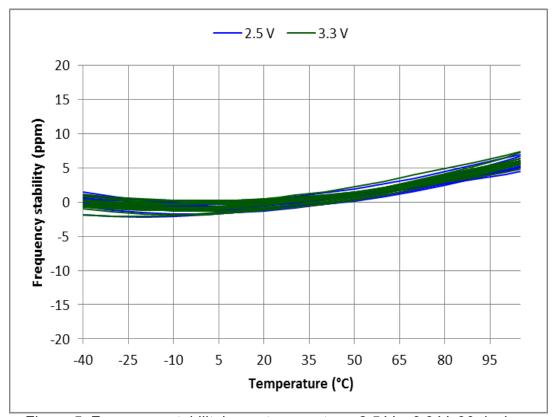


Figure 5: Frequency stability* over temperature, 2.5 V – 3.3 V, 30 devices

*SiT3372 frequency stability is independent of output frequency.



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Table 3: Summary performance data

Parameter	Units	Voltage		
Parameter	UTILS	2.5 V	3.3 V	
Period jitter	ps, rms	0.82	0.82	
Period jitter (sample size 10,000 cycles)	ps, pk-pk	6.16	6.22	
Duty cycle	%	50.0	50.2	
Rise time (20% - 80%)	ps	398	401	
Fall time (80% - 20%)	ps	385	376	
Differential voltage swing	V	0.81	0.80	
Current consumption (no load, output enabled)	mA	75.4	75.5	
Current consumption (no load, output disabled)	mA	57.9	57.9	



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Test description

Conditions:

- Frequency: 148.351648 MHz

- VDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

Equipment:

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



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Setup

Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 100 Ω differential. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

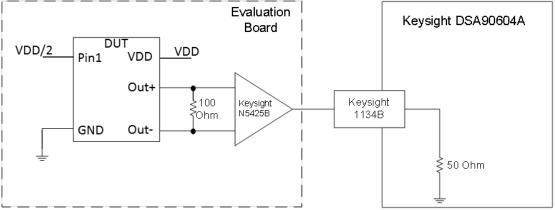


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

Period Jitter

For period jitter measurement outputs are connected through AC-coupling capacitors to the oscilloscope channels. Signals are subtracted inside the oscilloscope. All measurements applied to differential waveform. Figure 7 shows test setup diagram for period jitter measurement.

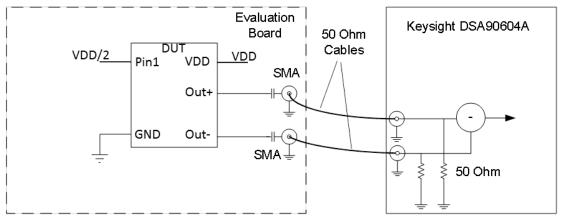
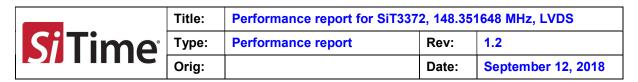


Figure 7. Test setup for measuring period jitter

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Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Figure 8 shows test setup diagram for phase noise measurement.

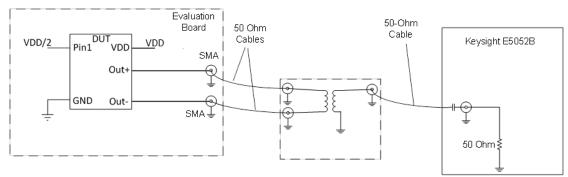


Figure 8. Test setup for measuring phase noise.

Current consumption

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.